Sea	rch Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/630,730	CHINA, HIROSHI	
Examiner	Art Unit	
Edgardo San Martin	2837	

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Class	Subclass	Date	Examiner
181	176,156 199,153 163,164 165,191	6/28/2005	ESM
381	339,345		7
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	424,432		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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